

<b>FORM PTO-1449 U.S. Department of Commerce</b> <b>Patent and Trademark Office</b>  <b>List of Documents Cited by Applicant</b>				Application No.:	10/615,842
				Filing Date:	July 10, 2003
				First Named Inventor:	Oh
				Group:	1795
				Examiner:	Phasge, Arun S.
				Attorney Docket No.:	421/170/8/2 CIP
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EXAMINER /Arun Phasge/ DATE CONSIDERED 10/09/2008

\*Examiner Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.